

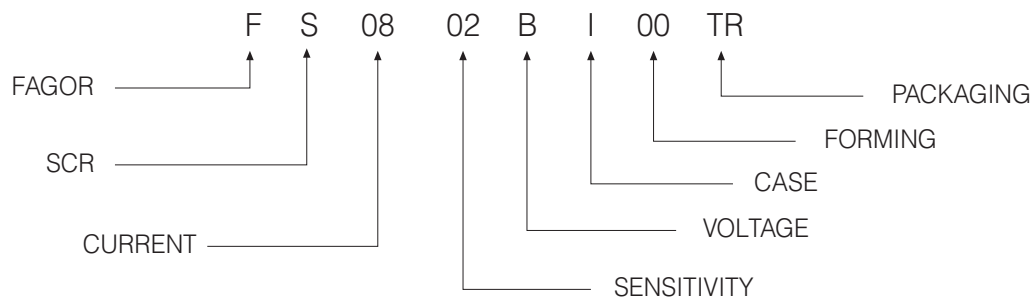


## SENSITIVE GATE SCR

### Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	SENSITIVITY		Uni
				02	
$I_{GT}$	Gate Trigger Current	$V_D = 12 V_{DC}, R_L = 140\Omega, T_j = 25^\circ C$	MIN MAX	200	$\mu A$
$V_{GT}$	Gate Trigger Voltage	$V_D = 12 V_{DC}, R_L = 140\Omega, T_j = 25^\circ C$	MAX	1.6	V
$V_{GD}$	Gate Non Trigger Voltage	$V_D = V_{DRM}, R_L = 3.3k\Omega, R_{GK} = 220\Omega, T_j = 125^\circ C$	MIN	0.1	V
$V_{RGM}$	Reverse Gate Voltage	$I_{RG} = 10\mu A,$	MIN	8	V
$I_H$	Holding Current	$I_T = 50 mA, R_{GK} = 1k\Omega, T_j = 25^\circ C$	MAX	5	mA
$I_L$	Latching Current	$I_G = 1 mA, R_{GK} = 1k\Omega$	MAX	6	mA
$dV / dt$	Critical Rate of Voltage Rise	$V_D = 0.67 \times V_{DRM}, R_{GK} = 1k\Omega, T_j = 125^\circ C$	MIN	5	V/ $\mu s$
$dI / dt$	Critical Rate of Current Rise	$I_G = 2 \times I_{GT}, tr \leq 100 ns, f = 60 Hz, T_j = 125^\circ C$	MIN	50	A/ $\mu s$
$V_{TM}$	On-state Voltage	at $I_T = 16 Amp, tp = 380 \mu s, T_j = 25^\circ C$	MAX	1.6	V
$V_{t0}$	Threshold Voltage	$T_j = 125^\circ C$	MAX	0.85	V
$r_d$	Dynamic resistance	$T_j = 125^\circ C$	MAX	46	$m\Omega$
$I_{DRM} / I_{RRM}$		$V_D = V_{DRM}, R_{GK} = 1k\Omega, T_j = 125^\circ C$ $V_R = V_{RRM}, T_j = 25^\circ C$	MAX	2	mA
			MAX	10	mA
$R_{th(j-c)}$	Thermal Resistance Junction-Case for DC	for AC 360° conduction angle		1.8	$^\circ C/W$
$R_{th(j-a)}$	Thermal Resistance Junction-Amb for DC	$S = 1 cm^2$		100	$^\circ C/W$

### PART NUMBER INFORMATION



**SENSITIVE GATE SCR**

Fig. 1: Maximum average power dissipation versus average on-state current.

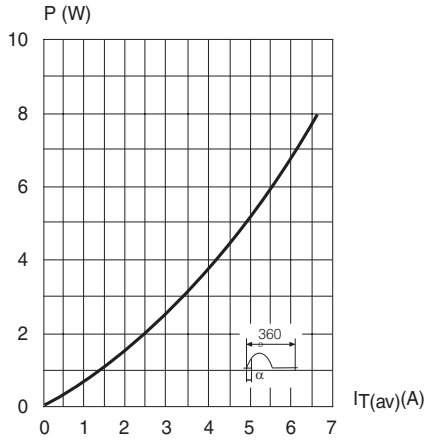


Fig. 2: Average and D.C. on-state current versus case temperature.

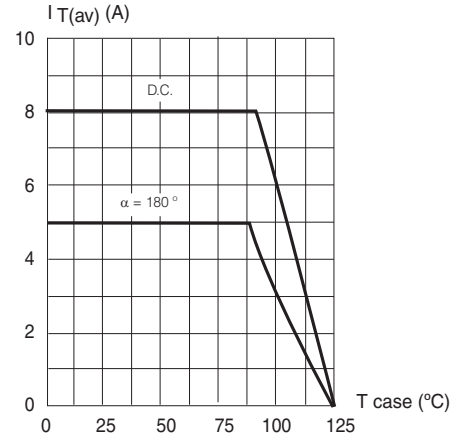


Fig. 3: Relative variation of thermal impedance junction to case versus pulse duration.

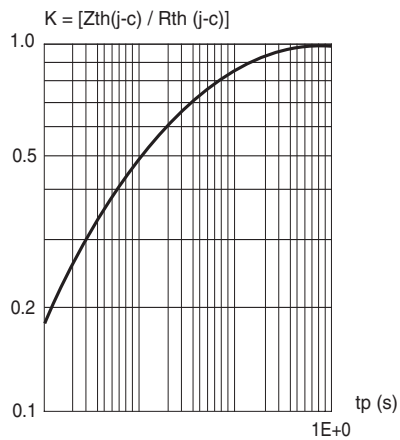


Fig. 4: Relative variation of gate trigger current, holding and latching current versus junction temperature.

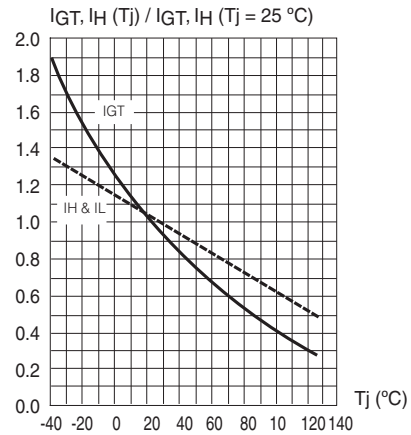


Fig. 5: Relative variation of holding current versus gate-cathode resistance (typical values).

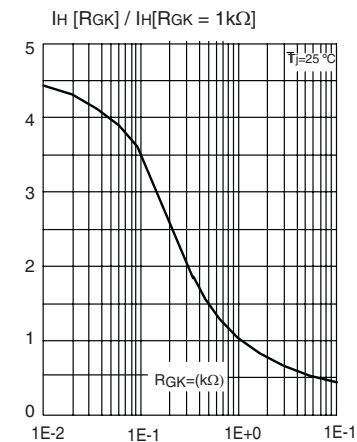
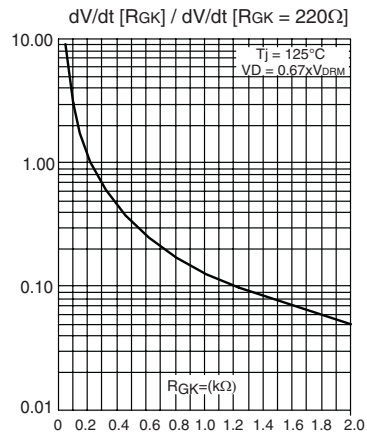


Fig. 6: Relative variation of dV/dt immunity versus gate-cathode resistance (typical values).



**SENSITIVE GATE SCR**

Fig. 7: Relative variation of  $dV/dt$  immunity versus gate-cathode resistance (typical values).

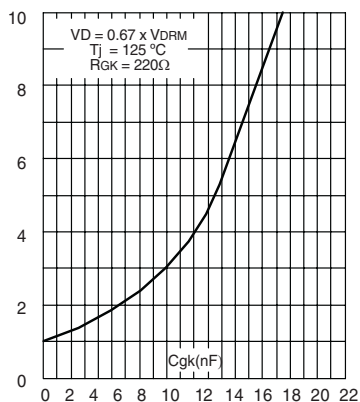


Fig. 9: Non repetitive surge peak on-state current for a sinusoidal pulse with width:  $t_p < 10$  ms, and corresponding value of  $I^2t$ .

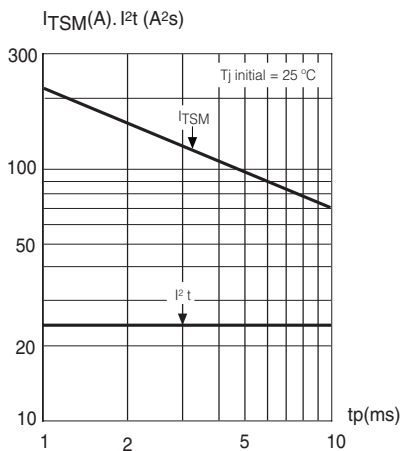


Fig. 8: Non repetitive surge peak on-state current versus number of cycles.

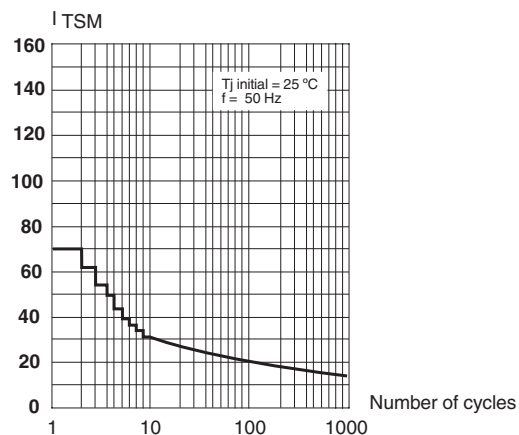
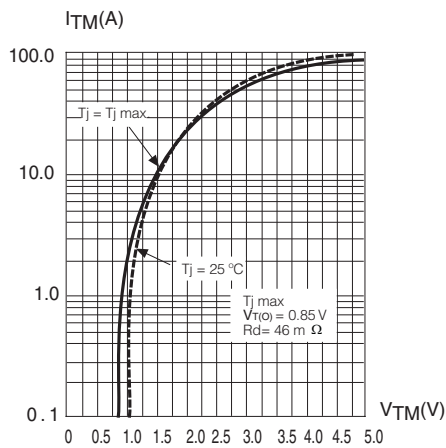


Fig. 10: On-state characteristics (maximum values).



**SENSITIVE GATE SCR**

**PACKAGE MECHANICAL DATA**

IPAK TO 251-AA

